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(12) **United States Design Patent** (10) **Patent No.:** **US D922,546 S**  
**Yoshida et al.** (45) **Date of Patent:** **\*\* Jun. 15, 2021**

(54) **COMPOSITE SEAL MEMBER FOR SEMICONDUCTOR PRODUCTION APPARATUS**

CPC ..... F16K 51/02; F16J 15/025; F16J 15/0887; F16J 15/104; F16J 15/128  
See application file for complete search history.

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(73) Assignee: **Valqua, Ltd.**, Tokyo (JP)

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(\*\*) Term: **15 Years**

(Continued)

(21) Appl. No.: **29/714,203**

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**Related U.S. Application Data**

CN	303747329 S	7/2016
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(Continued)

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(30) **Foreign Application Priority Data**

(57) **CLAIM**

Dec. 1, 2017 (JP) .....	2017026882
Dec. 1, 2017 (JP) .....	2017026887
Feb. 8, 2018 (JP) .....	2018002528

The ornamental design for a composite seal member for semiconductor production apparatus, as shown and described.

(51) <b>LOC (13) Cl.</b> .....	<b>23-01</b>
(52) <b>U.S. Cl.</b>	
USPC .....	<b>D23/269</b>
CPC .....	<b>F16J 15/025</b> (2013.01)

**DESCRIPTION**

(58) **Field of Classification Search**  
USPC ..... D15/7, 9, 11, 17, 21, 28, 123, 199;  
D23/269, 386, 259; D8/349;  
277/602-626; 285/95, 109, 336, 910, 918

FIG. 1 is a perspective view of a composite seal member for semiconductor production apparatus, showing our new design;  
FIG. 2 is a front elevation view thereof;  
FIG. 3 is a rear elevation view thereof;  
FIG. 4 is a left side elevation view thereof;  
FIG. 5 is a right side elevation view thereof;  
FIG. 6 is a top view thereof;  
FIG. 7 is a bottom view thereof;  
FIG. 8 is a cross-sectional view thereof; and,

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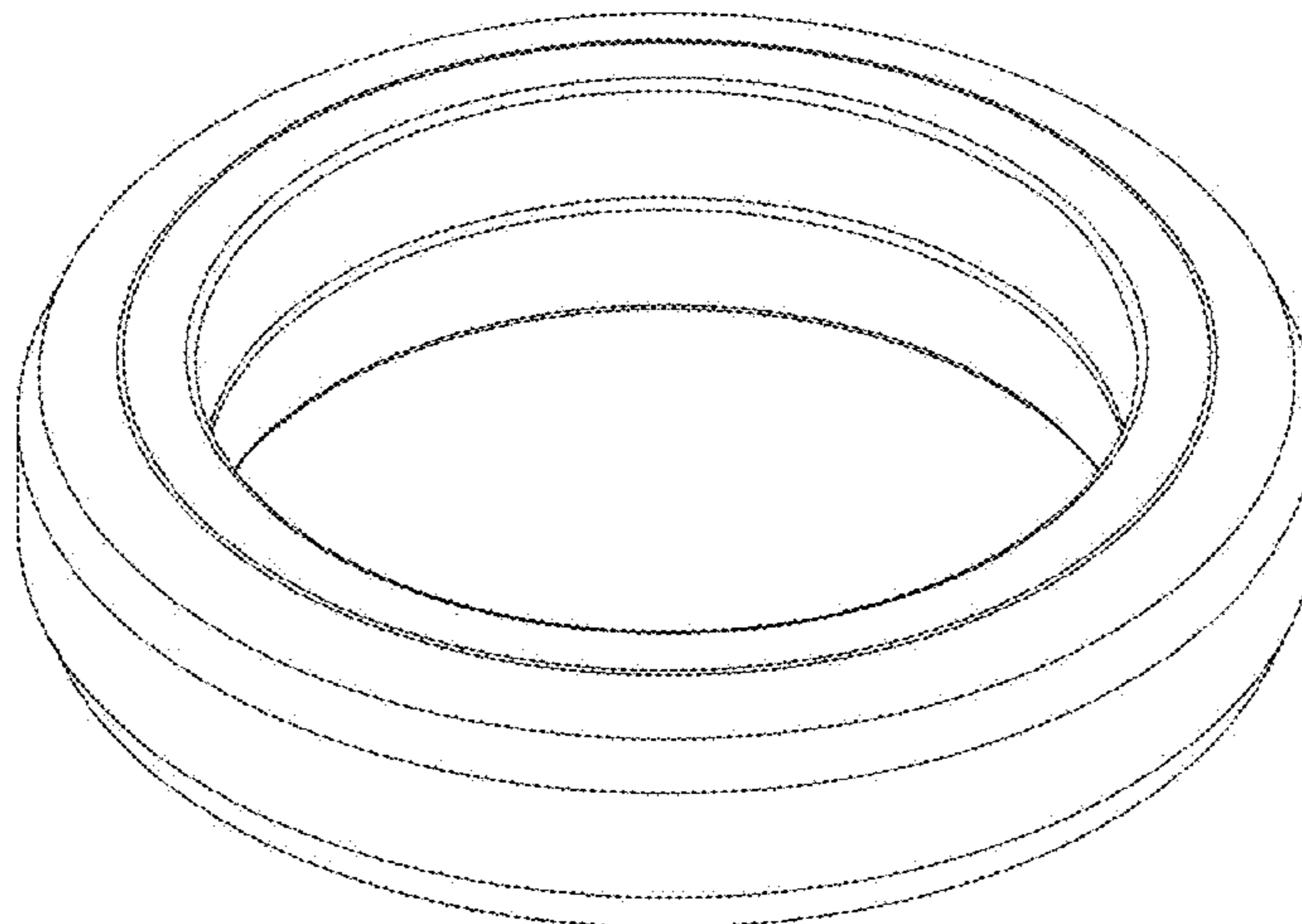


FIG. 9 is an enlarged cross-sectional view of a portion thereof.

**1 Claim, 9 Drawing Sheets**

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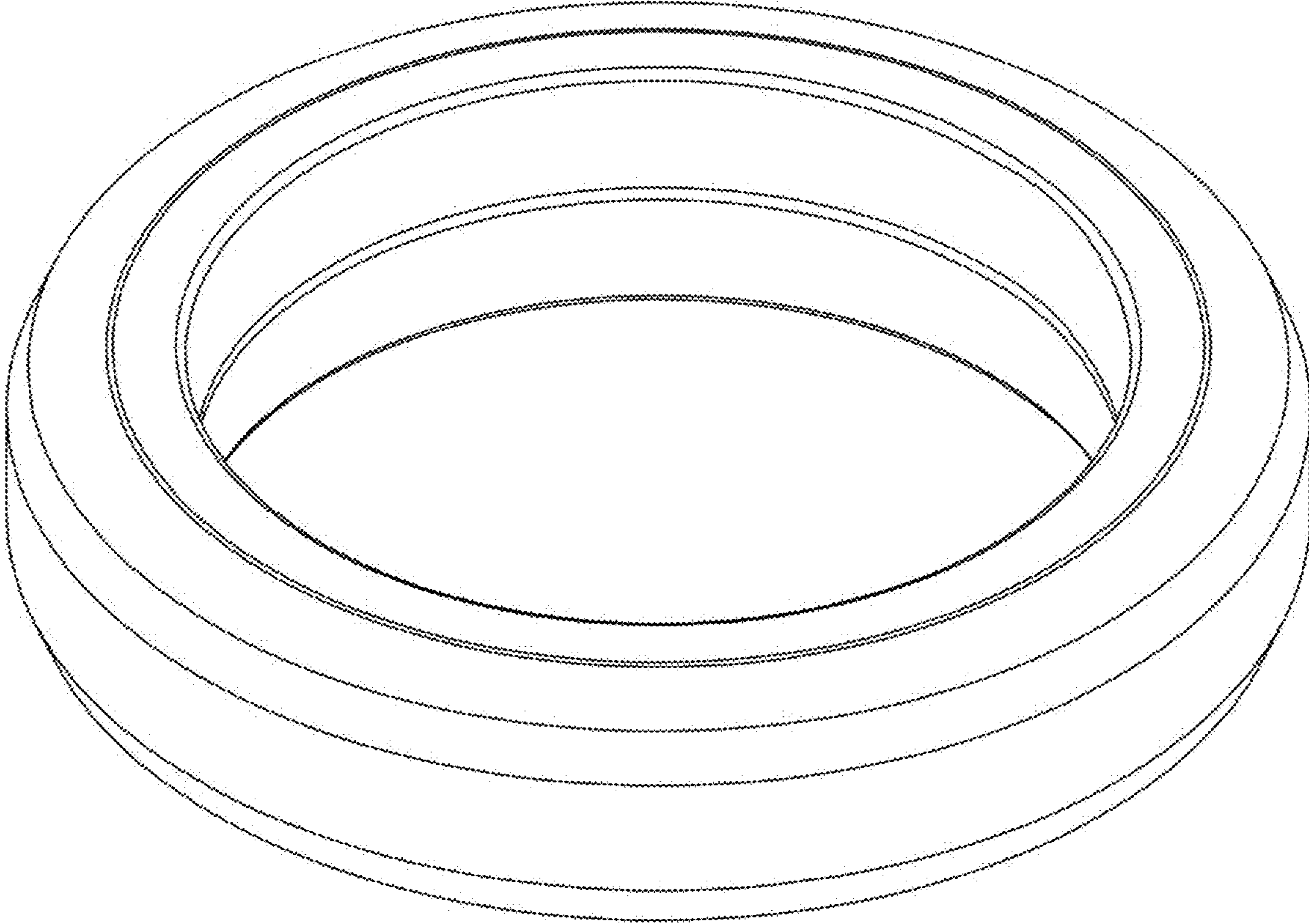
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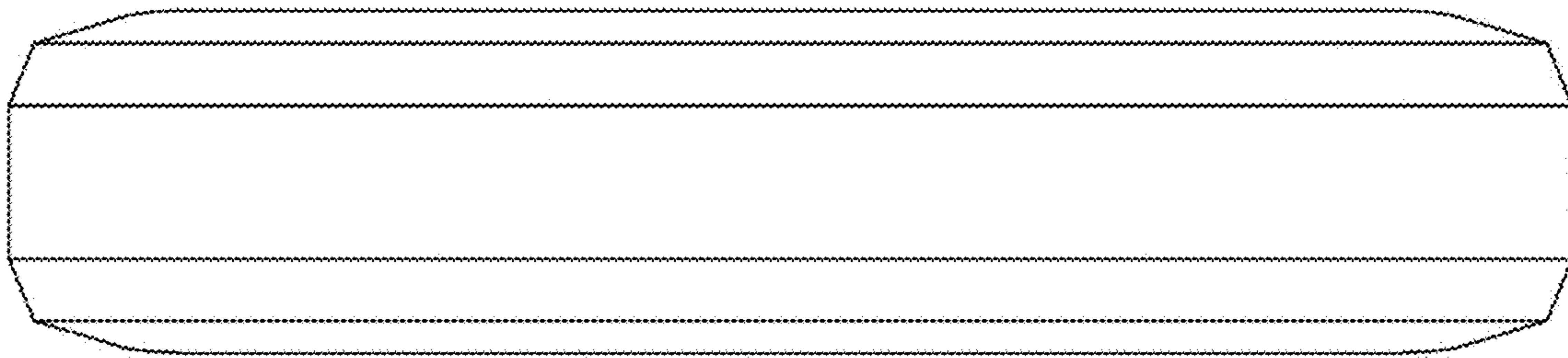
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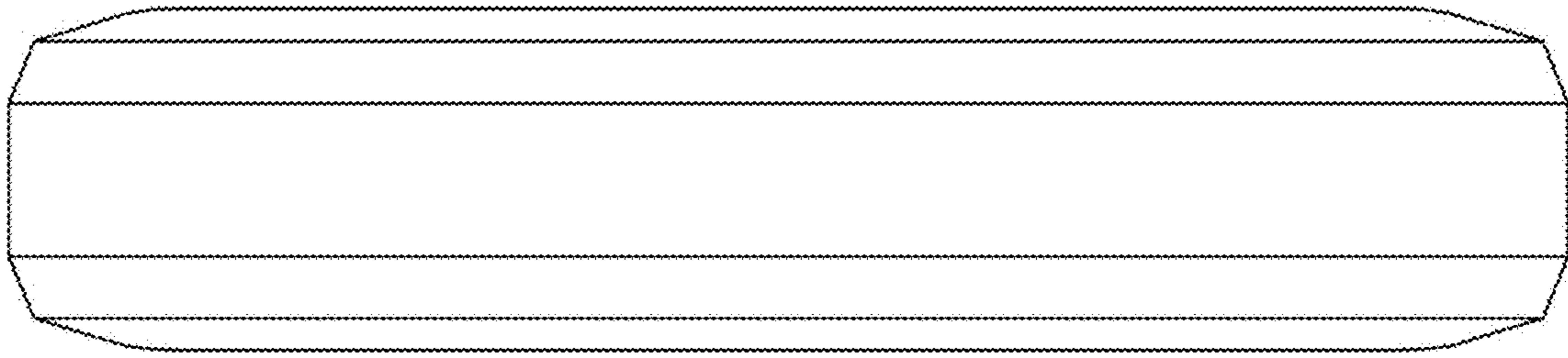
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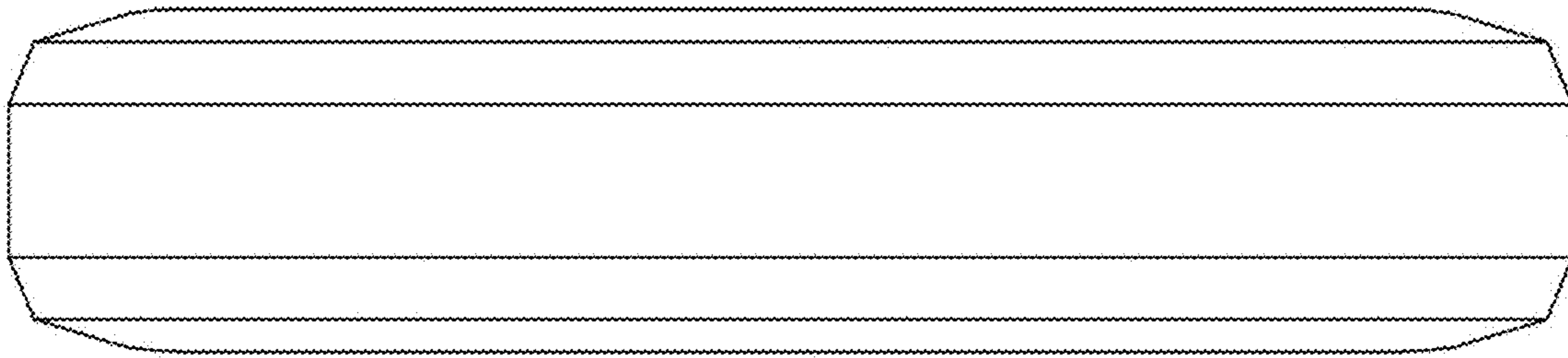
**FIG. 1**



**FIG. 2**



**FIG. 3**



**FIG. 4**

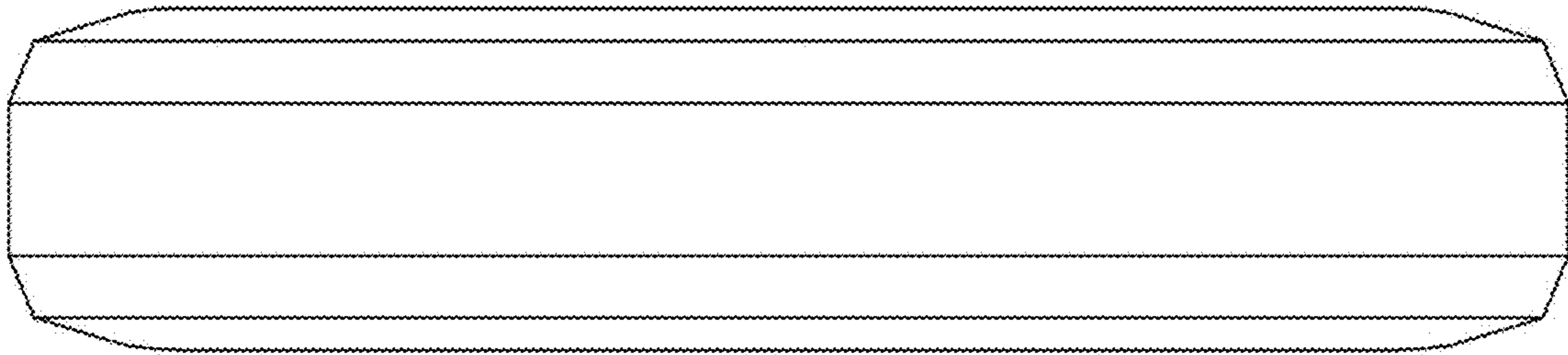


FIG. 5

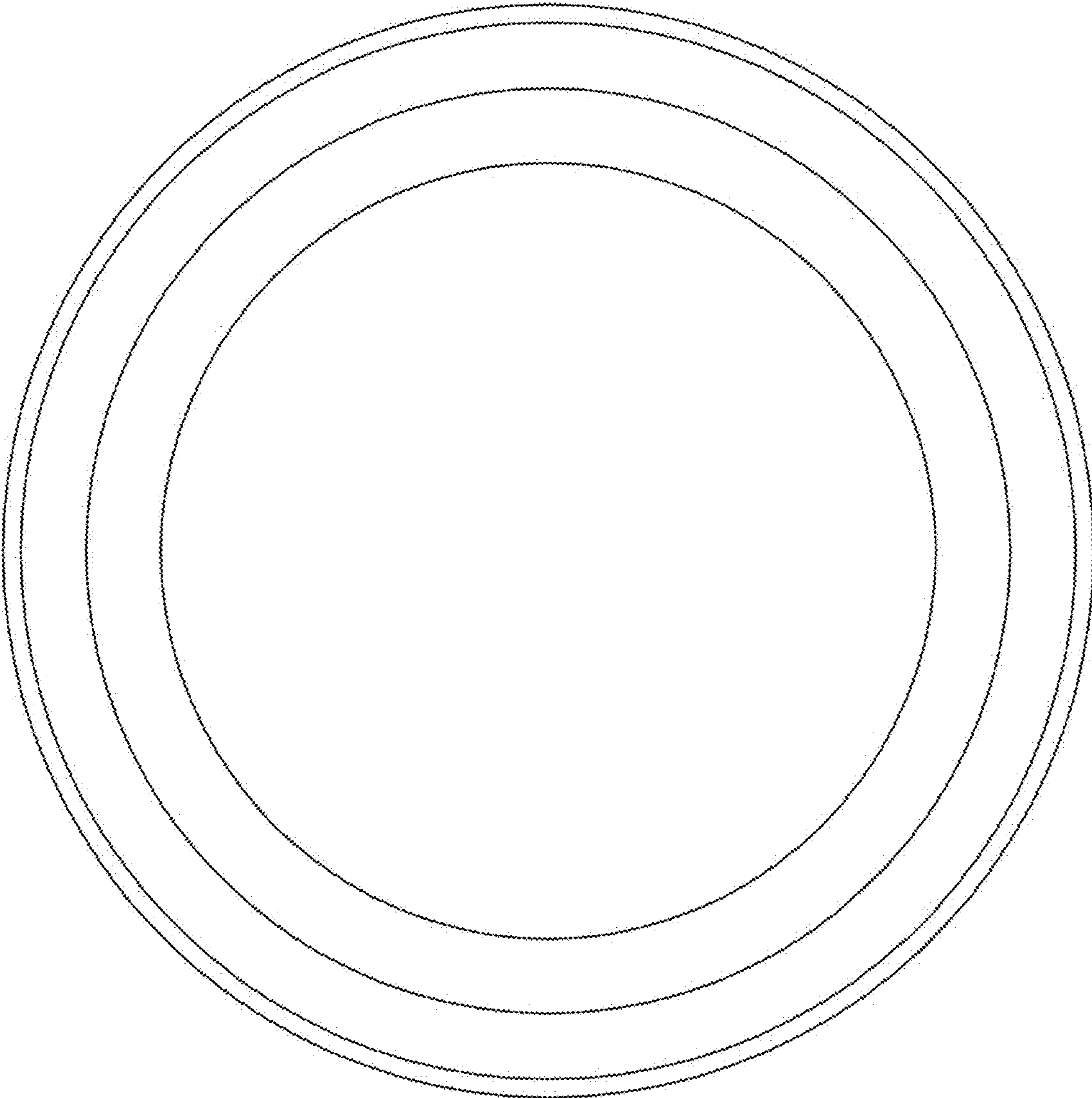


FIG. 6



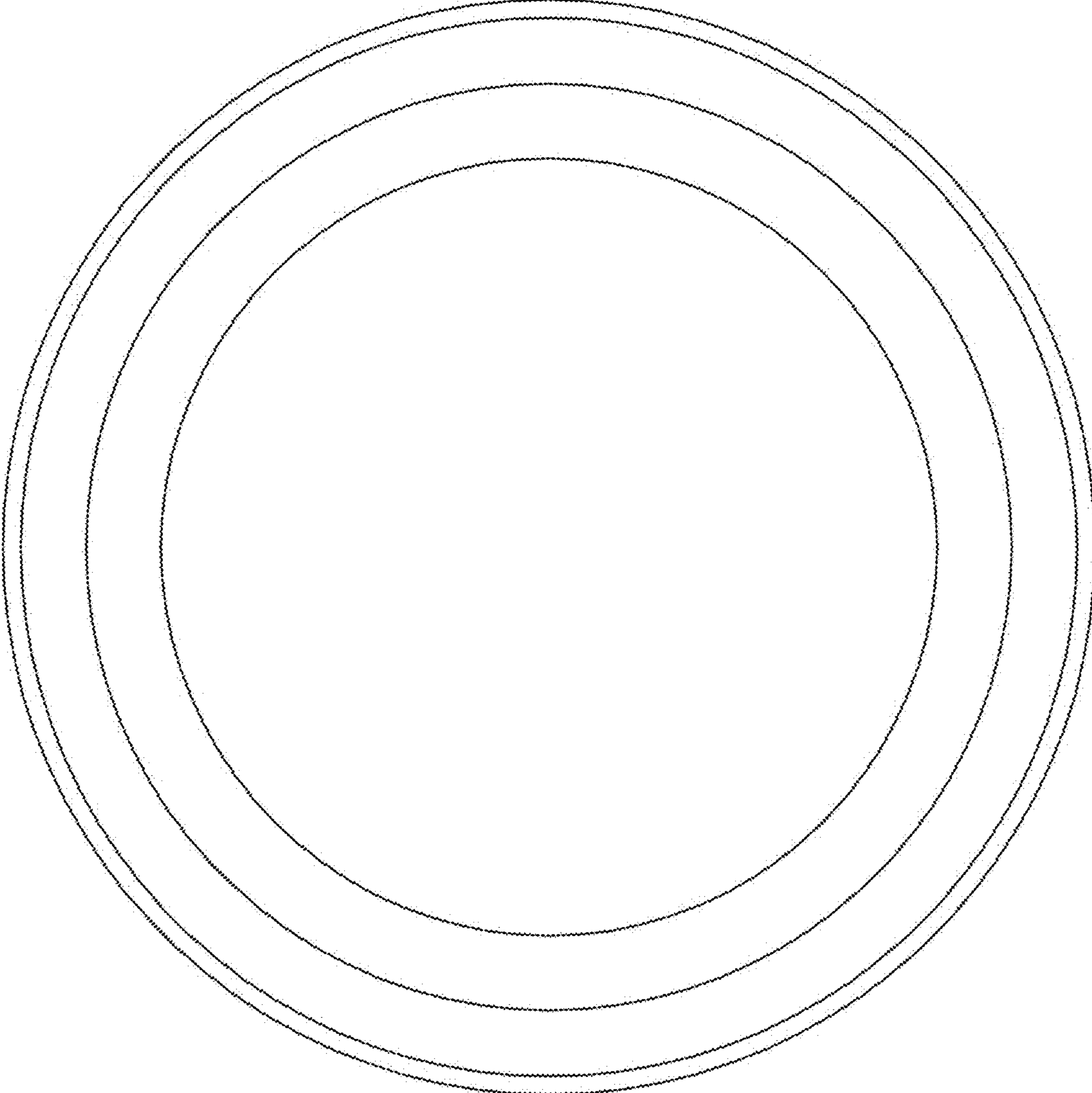


FIG. 7

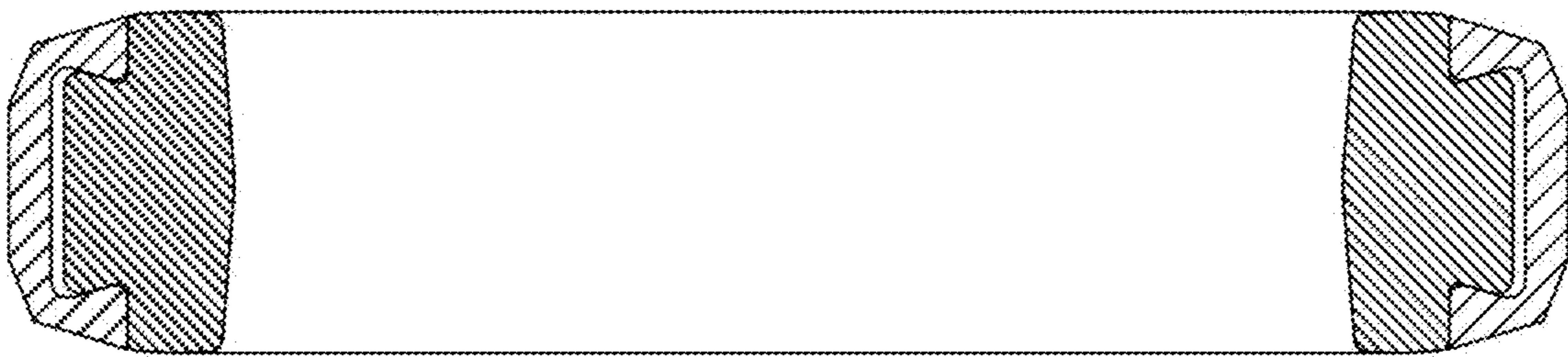


FIG. 8

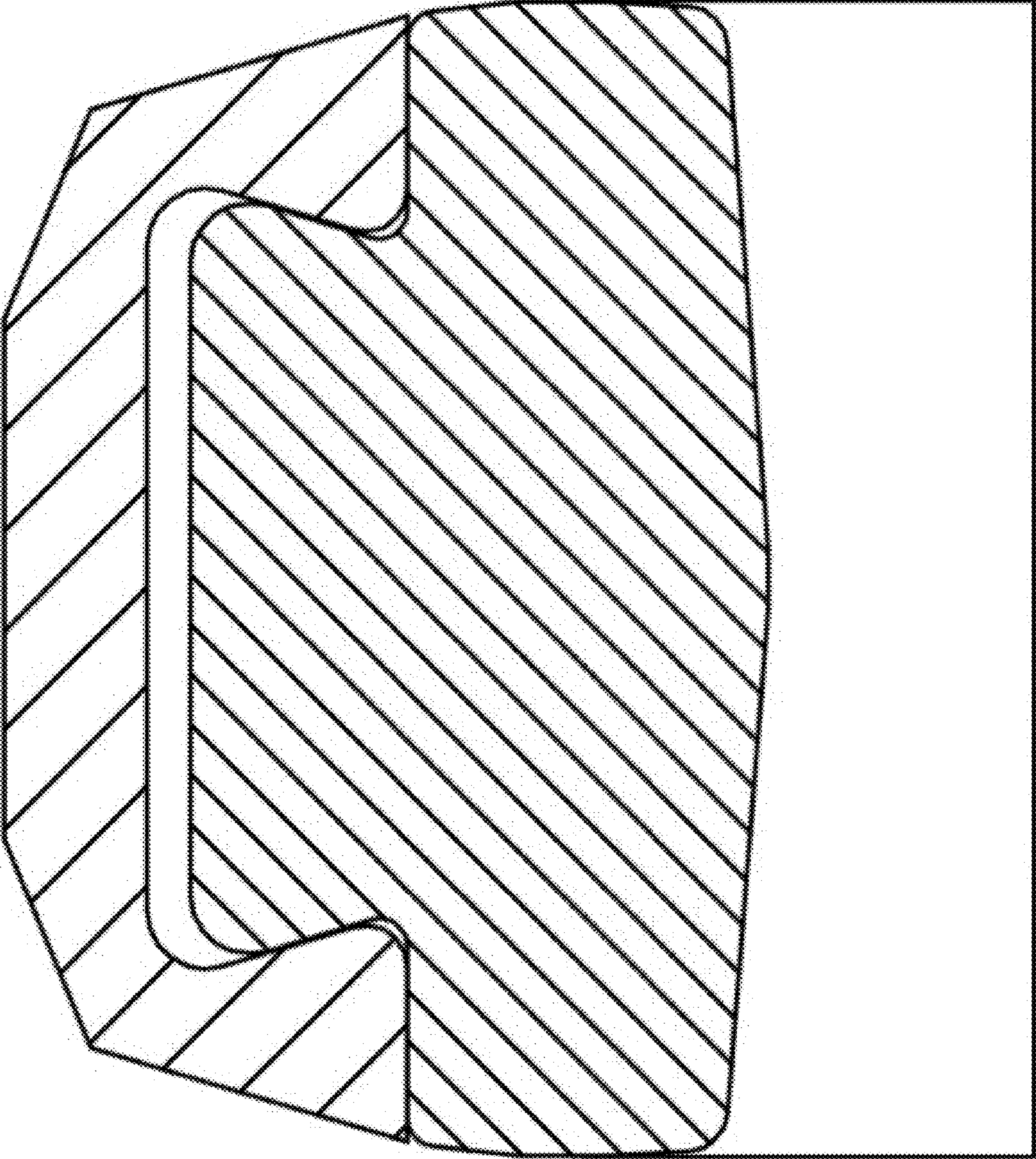


FIG. 9